

## Predicția fiabilității bazată pe fizica defectării

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### Reliability Prediction Based on the Physics-of-Failure

#### Abstract

*First, some methodologies used for reliability predictions are shown, in order to highlight the advantages of using the physics-of-failure (PoF) and, as an example of such methodologies, the procedure called SYRP (Synergetic Reliability Prediction) is detailed. Then, in the largest part of the paper, as a first step in using SYRP for reliability predictions, the typical failure mechanisms of integrated circuits are presented.*

**Keywords:** *reliability prediction, failure mechanisms, physics of failure.*